IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of Shunpei YAMAZAKI et al. Serial No. 09/699,466 √ Filed: October 31, 2000 For: METHOD FOR FABRICATING A)

SEMICONDUCTOR DEVICE

Art Unit: 2829

Examiner: A Sakar

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with The United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents,

AMENDMENT

Honorable Commissioner of Patents Washington, D.C. 20231

Sir:

In response to the Office Action dated August 6, 2002 please amend the aboveidentified application as follows:

IN THE CLAIMS:

Please cancel claims 4-34 and amend claim 1 as follows:

1. (Amended) A method for manufacturing a semiconductor device comprising:

forming a semiconductor film on an insulating surface;

forming a semiconductor island having a tapered shape by patterning said semiconductor film, said tapered shape having an angle within a range of 20° to 50° between a side thereof and an underlying surface;

forming a first gate insulating film over the semiconductor island wherein the first gate insulating film comprises silicon oxide;

forming a second gate insulating film over the first gate insulating film wherein the second gate insulating film comprises silicon oxide nitride;

forming a gate electrode over the semiconductor island with the first gate insulating film and the second gate insulating film therebetween; and

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